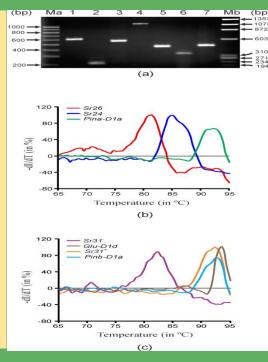
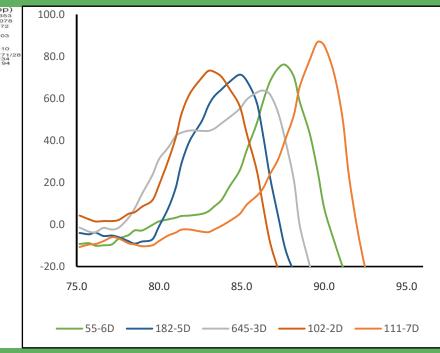
Gel -free screening of molecular markers in wheat (NABTD-MBD collaboration)



 Use of SYBR Green Melt Curve Based Screening, gel free screening of molecular markers (SCAR &STMS) have been developed for wheat.







RESEARCH ARTICLE

GLADS: A gel-less approach for detection of STMS markers in wheat and rice

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J. Crop Sci. Biotech, 2019 (December) 22 (4): 309 ~ 315 DOI No. 10.1007/s12892-017-0083-0

RESEARCH ARTICLE

Validation and Marker-Assisted Selection of Stem Rust Resistance Gene Sr2 in Indian Wheat Using Gel-Based and **Gel-Free Methods**

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Received: July 10, 2017 / Revised: May 02, 2018 / Accepted: May 28, 2018

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Plant Breeding, 135, 643-653 (2016) © 2016 Blackwell Verlag GmbH

doi:10.1111/pbr.12415

Rapid and convenient gel-free screening of SCAR markers in wheat using SYBR green-based melt-profiling

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With 4 figures and 4 tables

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Received July 10, 2015 / Accepted August 15, 2016 Communicated by L. Hartl